- (Previously Presented) A fin-type field effect transistor (FinFET) comprising:
 a first fin having a central channel region and source and drain regions adjacent said channel region;
- a gate structure intersecting said first fin and covering said channel region; and a second fin consisting of a channel region, said second fin being parallel to said first fin and being covered by said gate structure, and said channel region of said second fin is devoid of a connection to any source or drain regions.
- (Previously Presented) A fin-type field effect transistor (FinFET) comprising:

 a first fin having a central channel region and source and drain regions adjacent said
 channel region;
- a gate structure intersecting said first fin and covering said channel region; and a second fin consisting of a channel region, said second fin being parallel to said first fin and being covered by said gate structure wherein said second fin has a length equal to a width of said gate structure.
- (Previously Presented) A fin-type field effect transistor (FinFET) comprising:

 a first fin having a central channel region and source and drain regions adjacent said
 channel region;
- a gate structure intersecting said first fin and covering said channel region; and
 a second fin consisting of a channel region, said second fin being parallel to said first fin
 and being covered by said gate structure, wherein said first fin is longer than said second fin.
- 4. (Previously Presented) The FinFET in claim 1, wherein said source and drain regions of said first fin extend beyond said gate structure.

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- 5. (Previously Presented) A fin-type field effect transistor (FinFET) comprising: a first fin having a central channel region and source and drain regions adjacent said channel region;
- a gate structure intersecting said first fin and covering said channel region; and
 a second fin consisting of a channel region, said second fin being parallel to said first fin
 and being covered by said gate structure, wherein said second fin does not extend beyond said
 gate structure.
- 6. (Previously Presented) The FinFET in claim 1, further comprising source and drain contacts covering said source and drain regions of said first fin.
- 7. (Previously Presented) The FinFET in claim 1, wherein no contacts are positioned adjacent said second fin.
- 8. (Previously Presented) A fin-type field effect transistor (FinFET) comprising: a first fin having a central channel region and source and drain regions adjacent said channel region; and
- a second fin consisting of a channel region, wherein said channel region of said second fin is devoid of a connection to any source or drain regions.
- (Currently Amended) A fin-type field effect transistor (FinFET) comprising:

 a first fin having a central channel region and source and drain regions adjacent said
 channel region; and
- a second fin consisting of a said channel region, wherein said first fin is longer than said second fin.
- 10. (Currently Amended) The FinFET in claim 8, further comprising a gate intersecting said first fin and covering said channel region of said first fin.

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- 11. (Currently Amended) A fin-type field effect transistor (FinFET) comprising: a first fin having a central channel region and source and drain regions adjacent <u>said</u> channel region; and
- a second fin consisting of a said-channel region, wherein said second fin has a length equal to a width of said gate structure.
- 12. (Previously Presented) The FinFET in claim 10, wherein said source and drain regions of said first fin extend beyond said gate structure.
- 13. (Currently Amended) A fin-type field effect transistor (FinFET) comprising: a first fin having a central channel region and source and drain regions adjacent <u>said</u> channel region; and
- a second fin consisting of a said channel region, wherein said second fin does not extend beyond said gate structure.
- 14. (Previously Presented) The FinFET in claim 8, further comprising source and drain contacts covering said source and drain regions of said first fin.
- 15. (Previously Presented) The FinFETs in claim 8, wherein no contacts are positioned adjacent said second fin.
- 16-29 (Cancelled).

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